

SENpro



Spectroscopic Ellipsometer

- Cost-efficient
- Preset angle of incidence
- Step Scan Analyzer principle

SENTECH

Erfolg
durch Leistung



Spectroscopic ellipsometer SENpro with controller and laptop

Product description

The **SENpro** features easy operation, high measurement speed, and combined data analysis of ellipsometric measurements at different angles of incidence. It measures in the spectral range from 370 nm to 1,050 nm. The majority of applications to determine thickness and optical constants of single films and multilayer stacks can be performed easily.

The cost-effective table top ellipsometer **SENpro** comprises the VIS-NIR ellipsometer optics, 5°-step goniometer, sample platform, laser alignment, fiber coupled stabilized light source, and detection unit. The **SENpro** comes with the spectroscopic ellipsometer software **SpectraRay LT** for system control and data analysis including modeling, simulation, fitting, and presentation of data. Ready-to-use application files make the operation very easy even for beginners. **SpectraRay LT** supports computer controlled mapping for uniformity measurements.

The **SENpro** is focused on speed and accuracy for the measurement of thin films wherever they are applied. Applications range from extreme thin layers of 1 nm to thick layers of up to 15 µm. For a large variety of applications, predefined recipes are offered by **SpectraRay LT**.

SENpro Spectroscopic Ellipsometer

Cost-effective Spectroscopic Ellipsometer

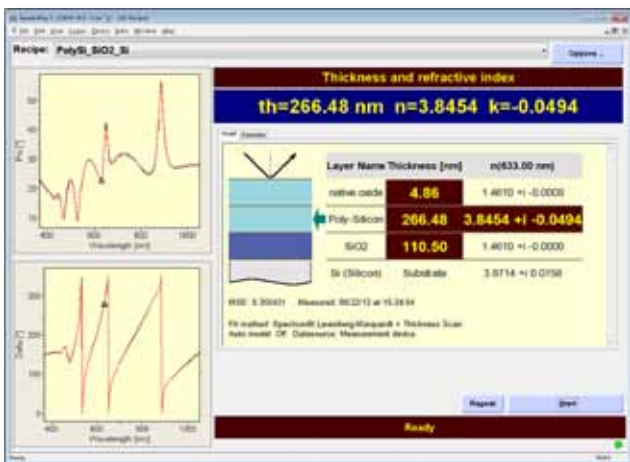
- Film thickness and optical constants between 370 nm and 1,050 nm wavelength
- Variable angle of incidence
- More than 500 wavelength points in a few seconds
- Easy-to-use recipe oriented software SpectraRay LT

Specifications

Spectral range:	370 nm – 1,050 nm UV-VIS
Measurement time:	Typical < 10 s for full spectra (more than 500 wavelength points)
Light source:	Stabilized Tungsten-Halogen lamp
Ellipsometer operation principle:	Step Scan Polarizer
Measurement spot size:	2 mm
Goniometer:	Mechanical goniometer, variable from 40° to 90°, set in 5° steps
Controller:	Comprising photo spectrometer, micro-controller, power supplies, LAN interface between (optional) PC and controller
Software:	SpectraRay LT operation and analysis software, models and fits single films and multilayer stacks, includes libraries for materials and dielectric models

Options

- Automatic mapping stages with 50 mm, 150 mm or 200 mm travel in x and y
- Liquid cell
- AFK
- **SpectraRay/3** software
- PC



SpectraRay LT software displaying measurement results

SENTECH Instruments GmbH

Schwarzschildstraße 2
12489 Berlin, Germany
Phone: +49 30 6392 5520
Fax: +49 30 6392 5522
E-Mail: info@sentech.de
www.sentech.de

Sales office

SENTECH Gesellschaft für Sensortechnik mbH

Konrad-Zuse-Bogen 13
82152 Krailling, Germany
Phone: +49 89 897 9607-0
Fax: +49 89 897 9607-22
E-Mail: sales@sentech.de
www.sentech-sales.de



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